

In the Specification:

Replace the paragraph on page 4, lines 12-22, with --

B1
with this
The use of external test connecting contact points allow
internal chip signals to be seen and the timing to be ^{how} *long*
determined accurately. For this purpose, a reference signal is
selectively applied to one of the external test connecting
contact points such that it can be passed on via a route ^{not shown in fig.} *(NA shown in fig.)*
within the component to a circuit point which is not
externally accessible. ^{External} Signals which are to be measured or
are to be analyzed can in each case be selectively applied
such that they can be passed on via routes within the
component from circuit points which are not externally
accessible to the other test connecting contact points. --